

EXHIBIT B

Bounding uncertainty in the static timing analysis of digital PD-SOI circuits

(with application to static noise analysis)

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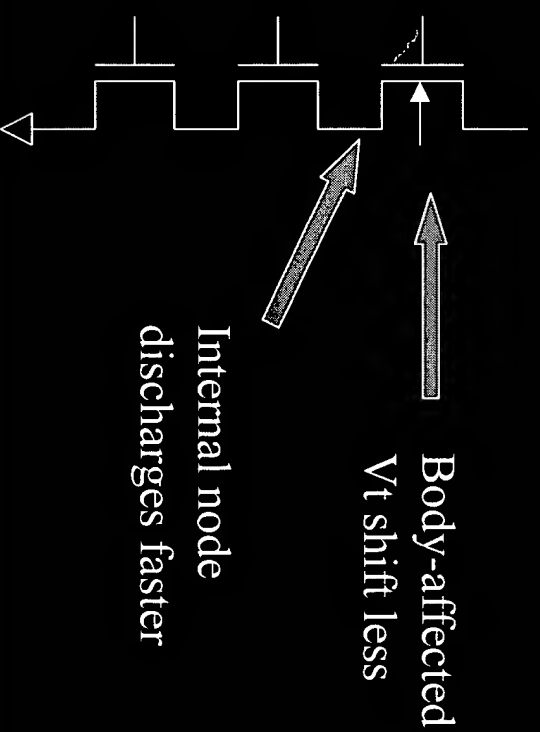
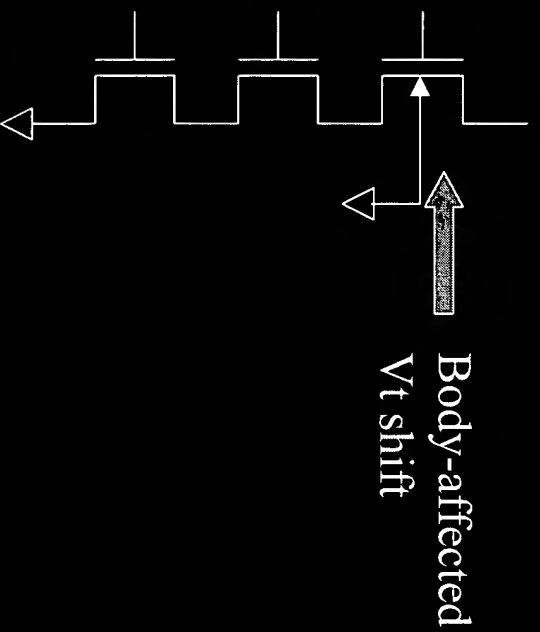
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Columbia University, New York, NY



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Advantages of SOI

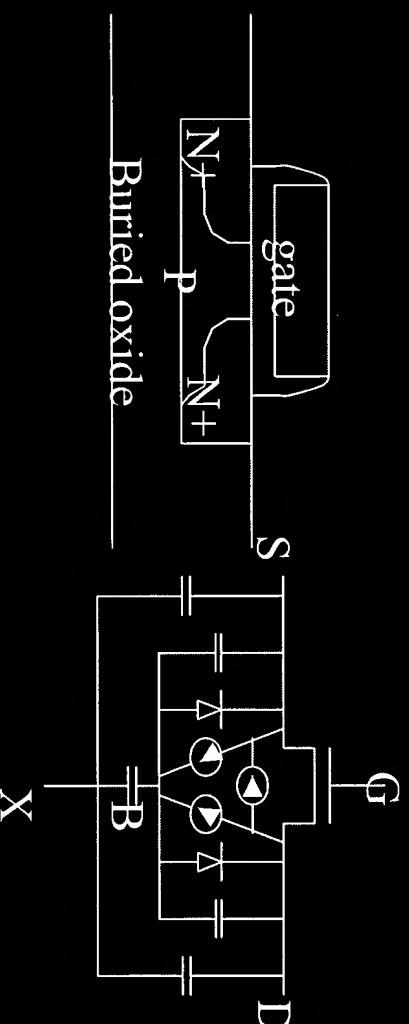
- Reduced source/drain diffusion capacitance
- Improved stack performance
- Some reduction in wire capacitance
- Gives advantage to certain circuit families (e. g. passgates)



Target technology for experiments

- IBM Sematech “benchmark” technology
 - $L_{\text{drawn}} = 0.35 \text{ } \mu\text{m}$
 - $T_{\text{ox}} = 4.5 \text{ nm}$
 - $T_{\text{box}} = 80 \text{ nm}$
- Core simulation technology is spice3f5 wrapped with an API and BSIM3-SOI models. Still debugging transient analysis accuracy!

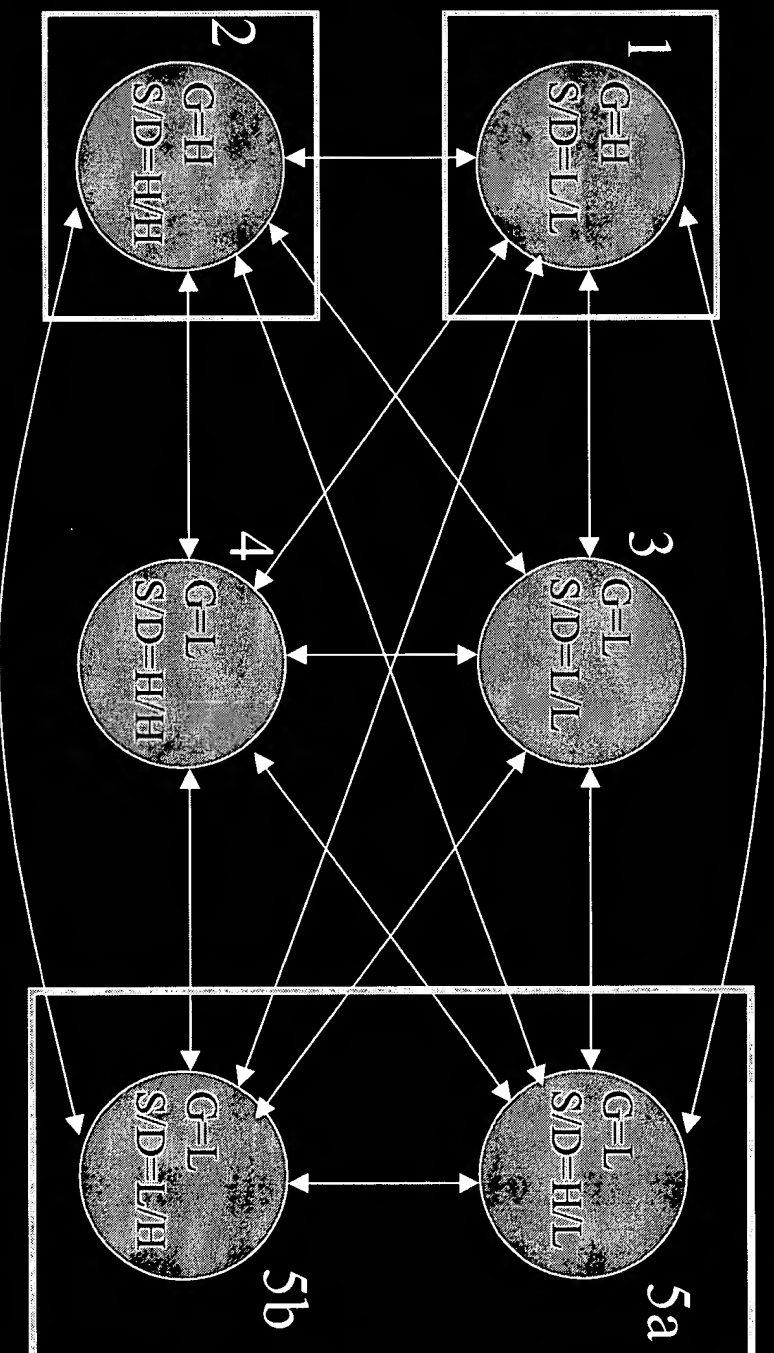
Body voltage determined by...



- Capacitive coupling of gate, substrate, source, and drain
- Forward-bias diode currents at the source-body and drain-body junctions
- Reverse-bias diode currents at the source-body and drain-body junctions

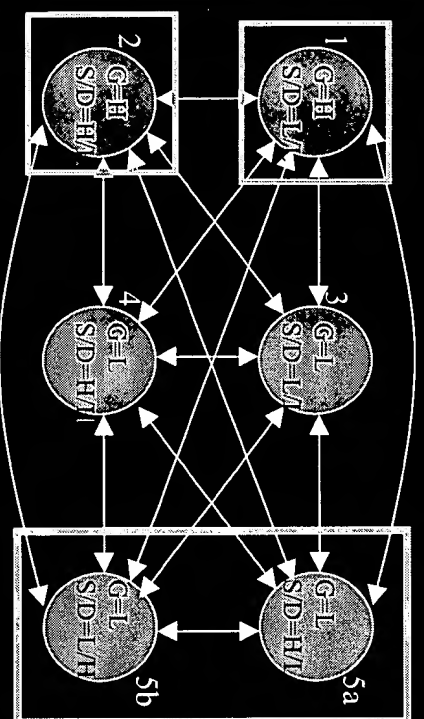
State diagram view of body interactions

nMOS



Device physics in this picture

Each state transition involves a “capacitive” coupling kick:

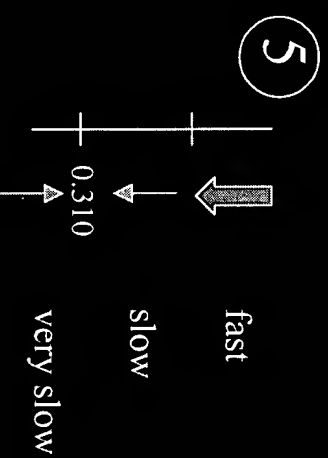
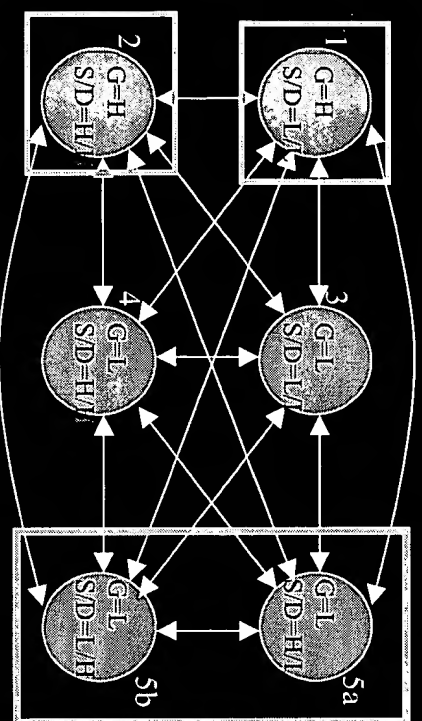


Capacitive kicks largely “reversible” except for cases of forward-bias body discharge. But are important for “initial condition” analysis.

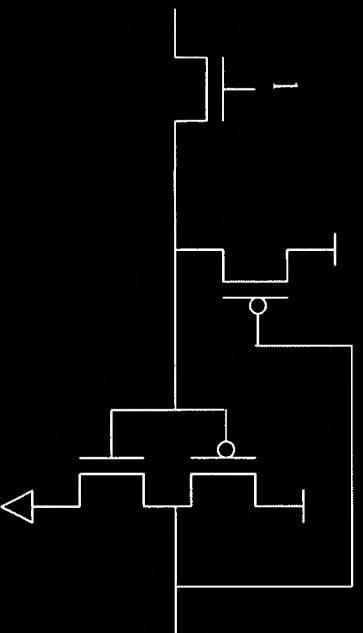
1->2	1200 mV
1->3	-300 mV
1->4	-200 mV
1->5	-200 mV
2->1	-950 mV/-1700 mV
2->3	-1300 mV/-2100 mV
2->4	-1450 mV/-950 mV
2->5	-16 mV/-1800 mV
3->1	300 mV
3->2	1650 mV
3->4	125 mV
3->5	95 mV
4->1	200mV/-1500 mV
4->2	1450 mV/950 mV
4->3	-110 mV/-1500 mV
4->5	-20 mV/-1300 mV
5->1	200 mV
5->2	1500 mV
5->3	-95 mV
5->4	20 mV

Device physics in this picture

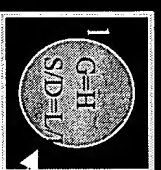
Each state has a steady-state target with relaxation time dependent on deviation from the target.



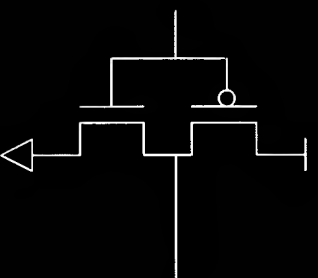
“Initial condition” analysis



Init max = 3.4 V

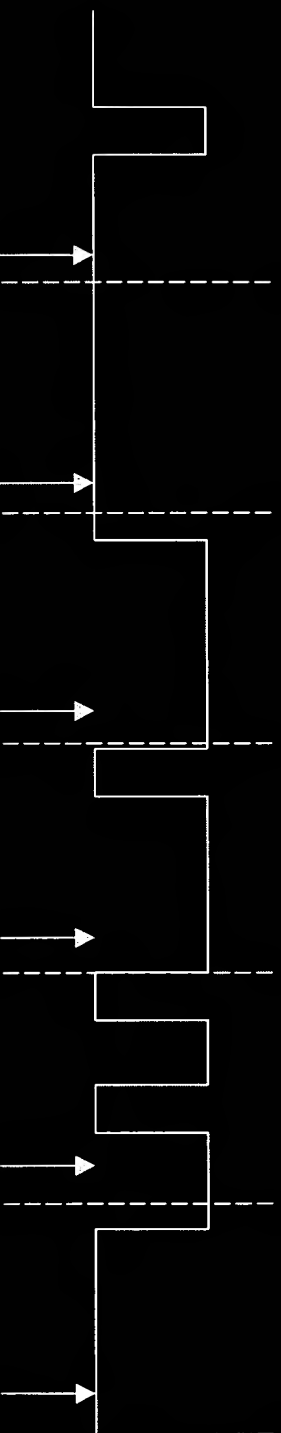
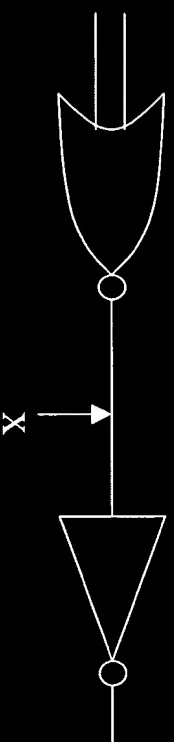


Init min = -0.2 V



Signal Probability

$P_s(x)$ = Average fraction of clock cycles in which the steady state value of x is a logic high

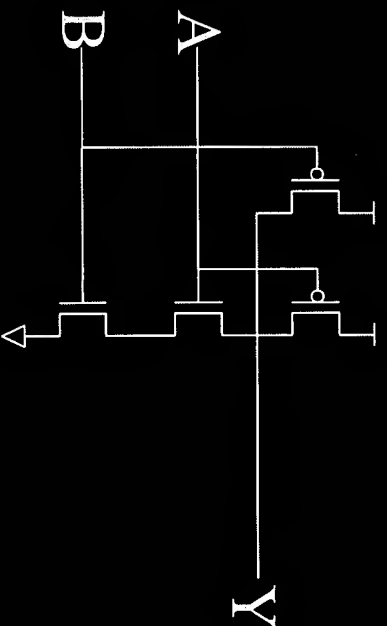


Signal Probability

$$P_s(A) = 0.5$$

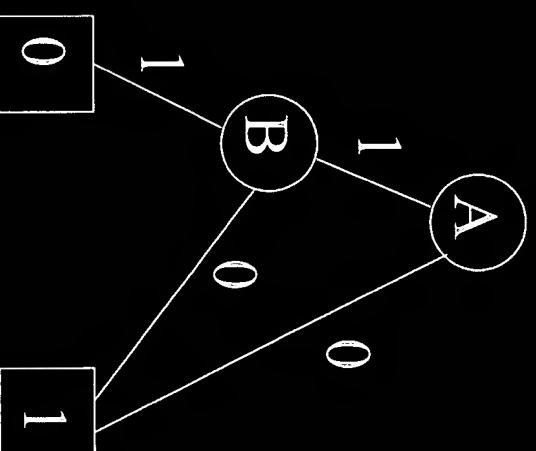
$$P_s(B) = 0.5$$

$$P_s(Y) = 1 - P_s(A)P_s(B) = 0.75$$



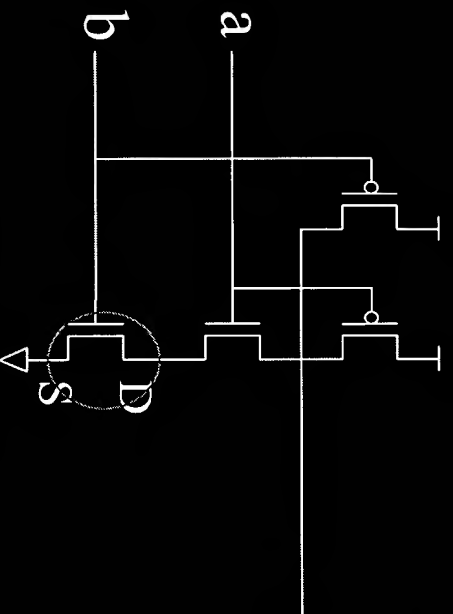
Easily done with BDD techniques

$$P(\hat{A}) + P(A)P(\hat{B})$$



Conditional channel switching probabilities

Do NOT sum to 1

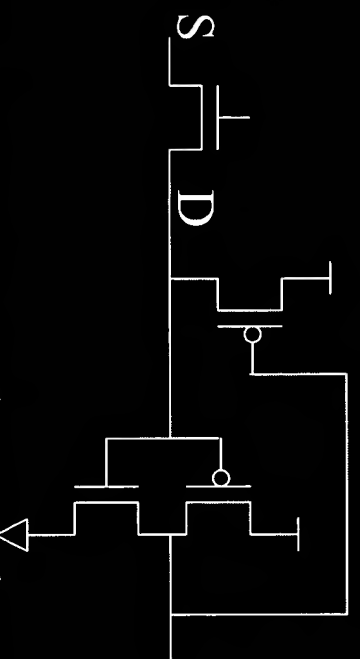


$$\begin{aligned} P(D|\wedge b) &= P(a) \\ P(\wedge D|\wedge b) &= 0 \end{aligned}$$

$$\begin{aligned} P(S|\wedge b) &= 0 \\ P(\wedge S|\wedge b) &= 1 \end{aligned}$$

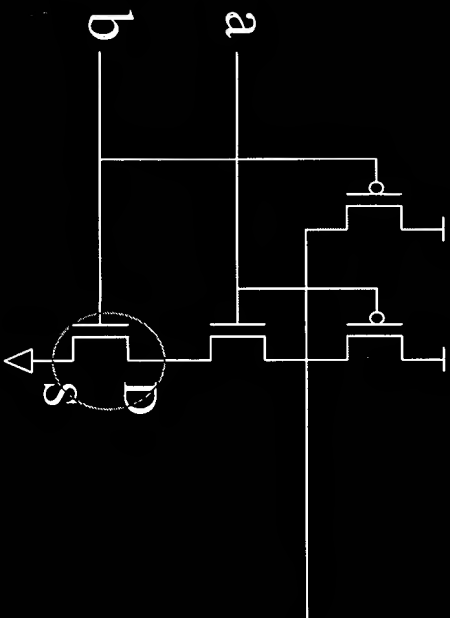
$$\begin{aligned} P(S|b) &= 0 \\ P(\wedge S|b) &= 1 \end{aligned}$$

$$\begin{aligned} P(S|G) &= 0.5 & P(D|\wedge G) &= 0 \\ P(\wedge S|G) &= 0.5 & P(\wedge D|\wedge G) &= 0 \\ P(\wedge S|\wedge G) &= 0.5 \\ P(S|\wedge G) &= 0.5 \end{aligned}$$



Done through a path search assuming both temporal and spatial independence of CCC input variables.

Hazards



a

b

b = H

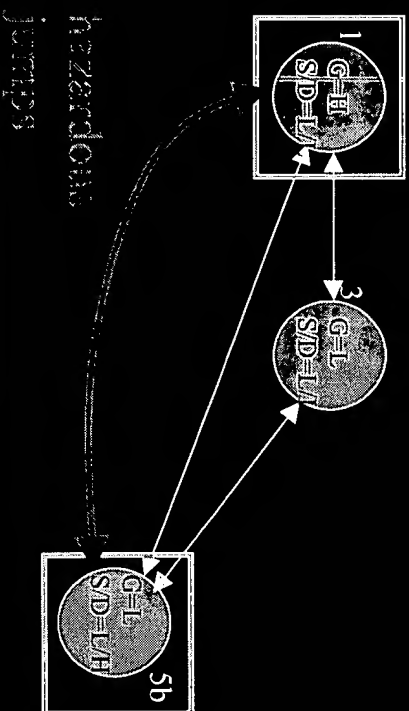
b = L

R max/min = 200/800
F max/min = 200/800

R max/min = 400/600
F max/min = 400/600

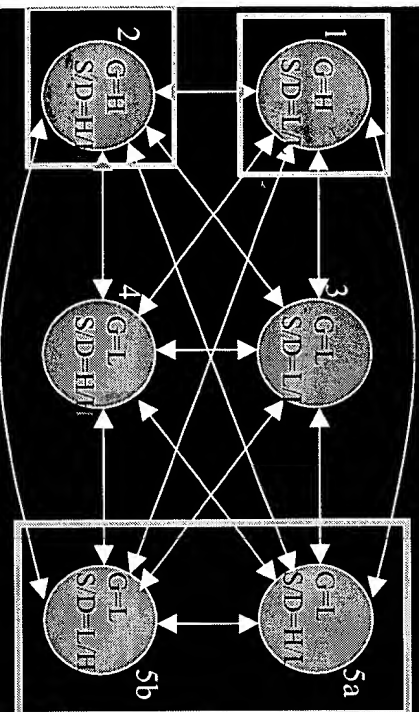
D F max = 600
D F min = 400
D R max = NA
D R min = NA

D R max = 800
D R min = 200
D F max = NA
D R min = NA



Monte Carlo analysis

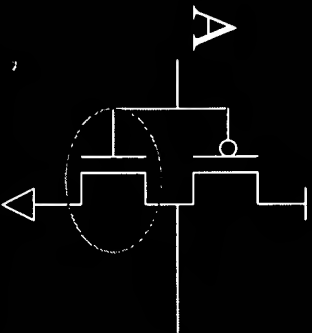
Inputs



signal probability of gate
channel conditional probabilities on
gate disposition
channel conditional hazard R/F times
on gate disposition
Process (done separately for min and max)
use first two cycles to establish initial
condition

then use probabilities:
assign next gate using signal probability
given next gate assignment, find S/D
assignment
given current state and next state, affect
transition to achieve min/max
result, allowing hazards

Monte Carlo results

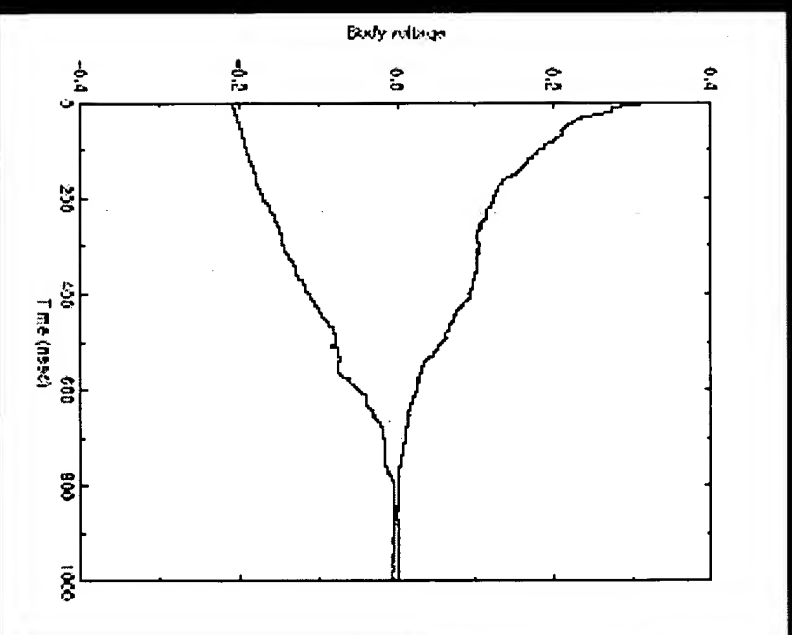


$$G/S/D = L/L/H$$

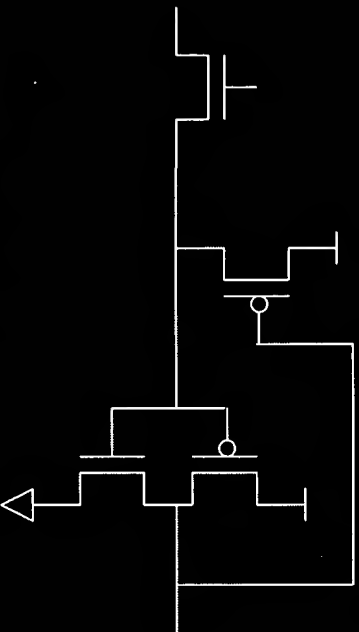
$$P(A) = 0.5$$

$$T_{\text{cycle}} = 1000 \text{ psec}$$

$$R/F \text{ min/max} = 400 \text{ ps} / 600 \text{ ps}$$



Monte Carlo results (con't)

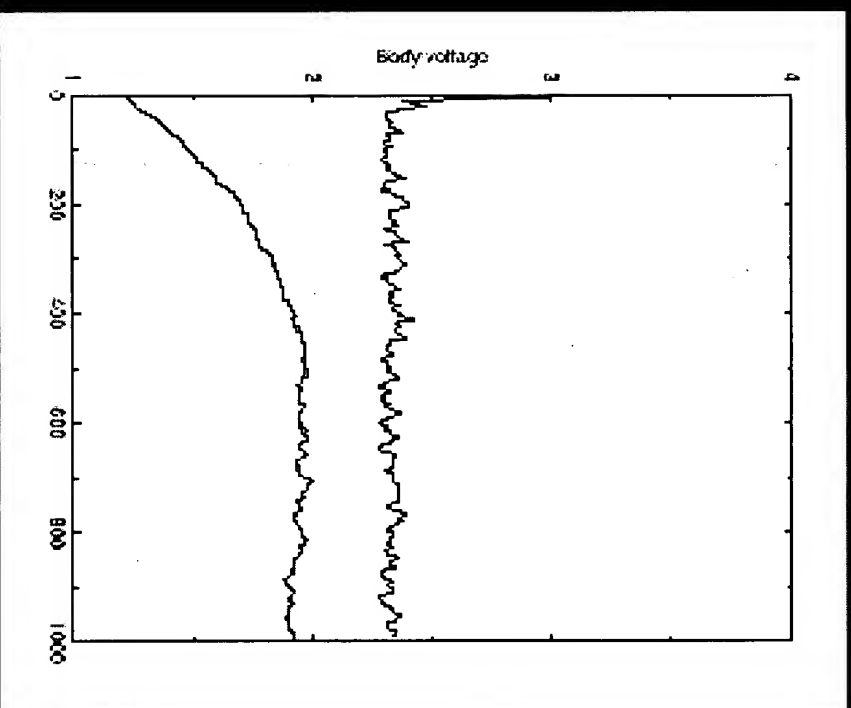
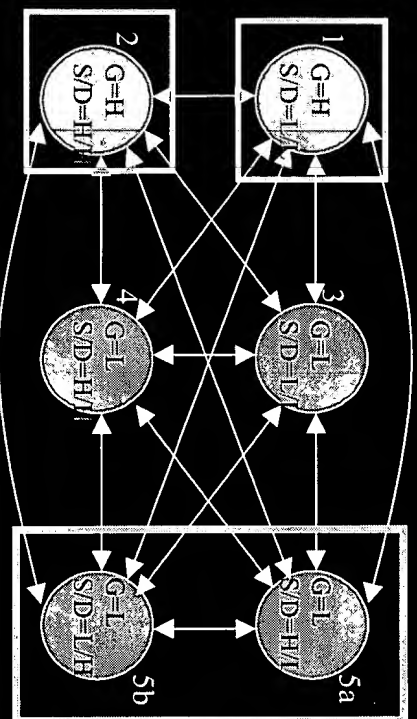


$G/S/D = H/H/H$

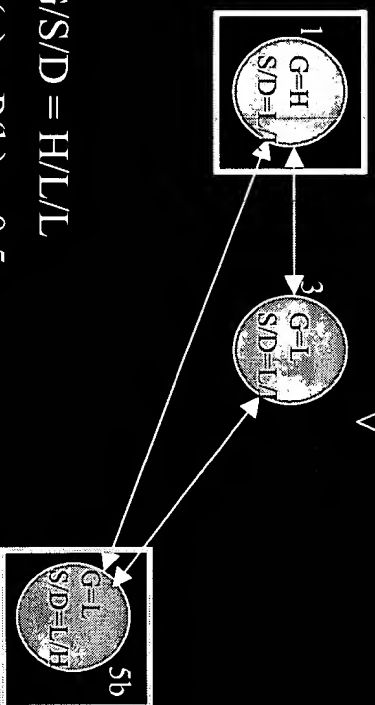
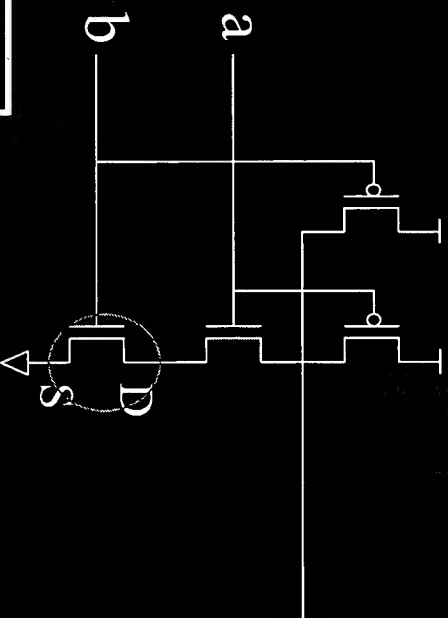
All probabilities are 0.5

$T_{\text{cycle}} = 1000 \text{ psec}$

$R/F \text{ min/max} = 400 \text{ ps} / 600 \text{ ps}$



Monte Carlo results (con't)

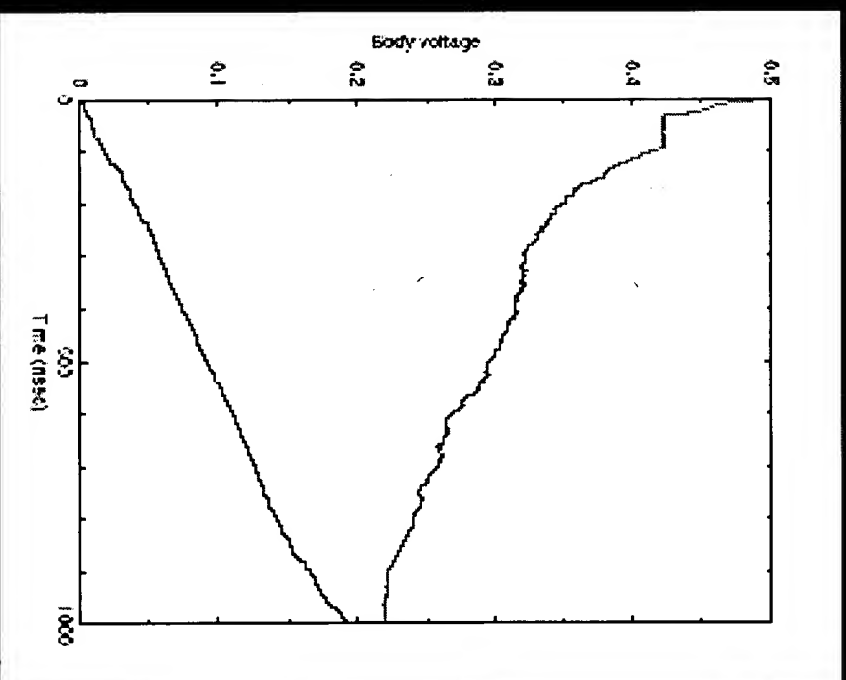


$G/S/D = H/L/L$

$P(a) = P(b) = 0.5$

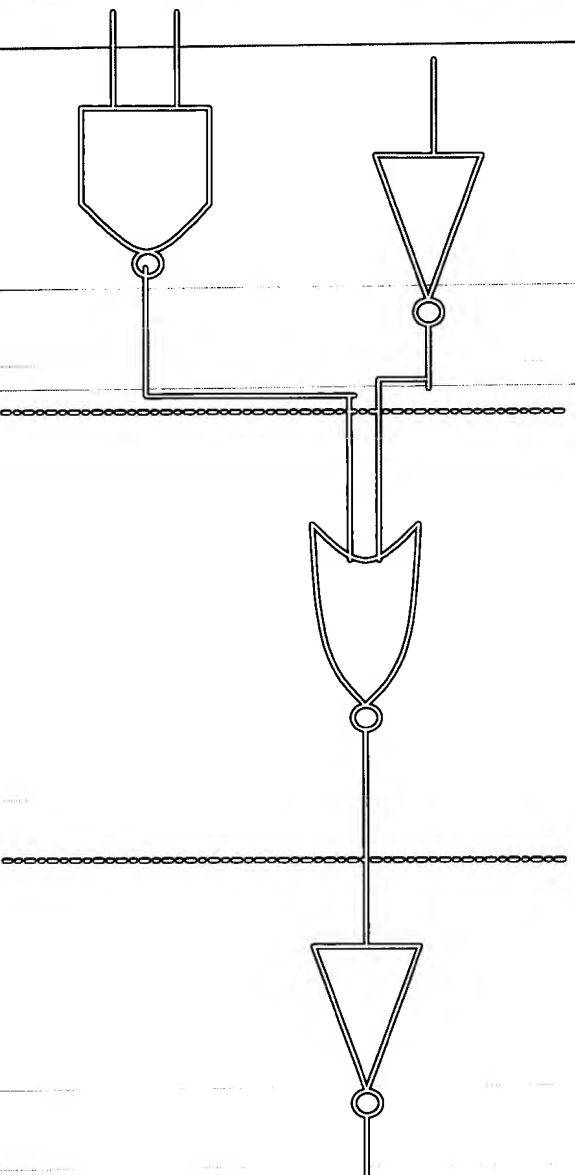
$T_{\text{cycle}} = 1000 \text{ psec}$

$R/F \text{ min/max} = 400 \text{ ps} / 600 \text{ ps}$



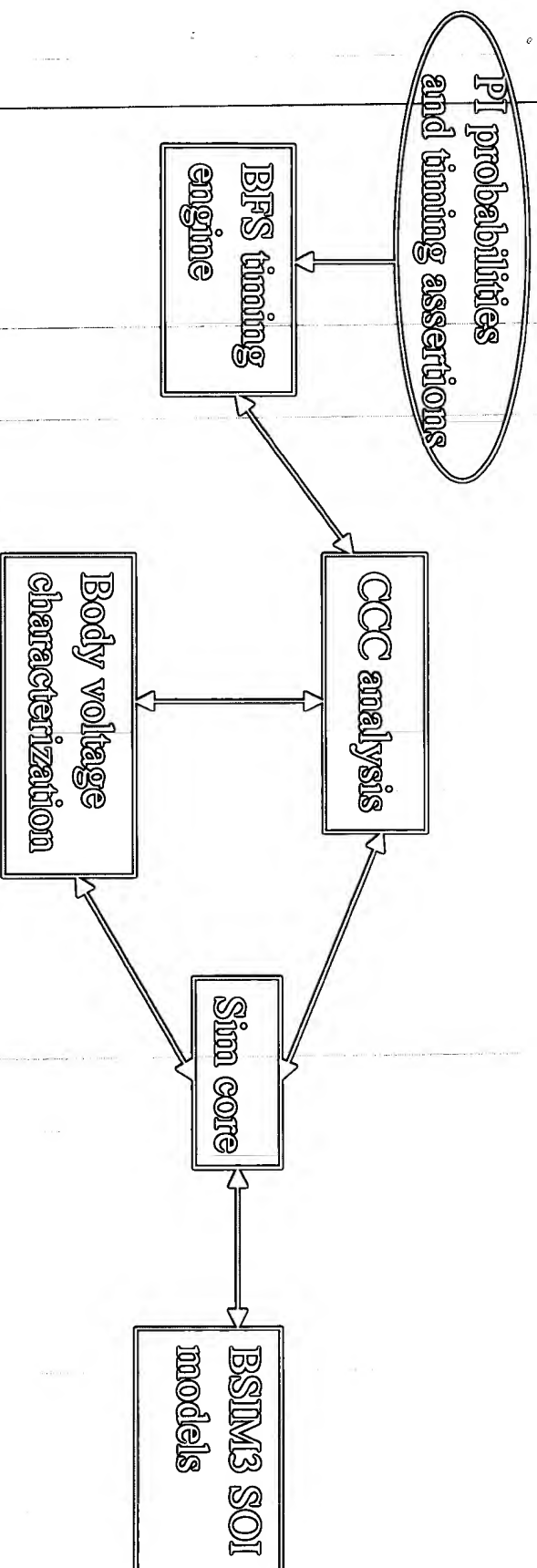
Integrated static timing and body voltage analysis

BFS transistor-level static timing analysis engine



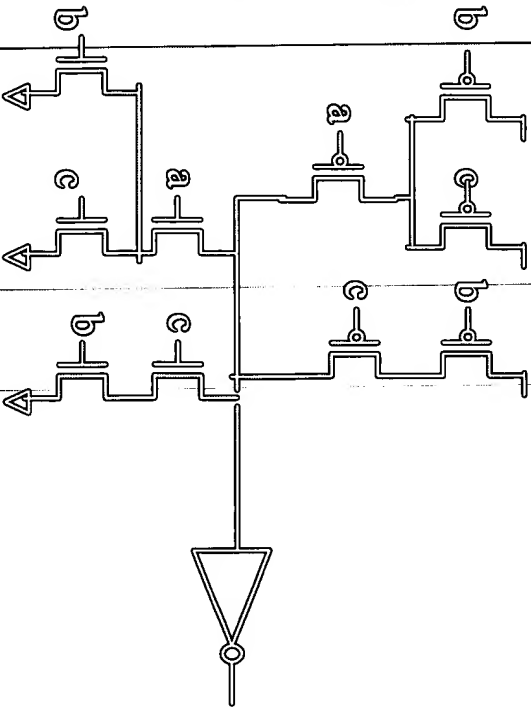
Full PWL waveform propagation
Waveform-delay “morphing”

Architecture of prototype



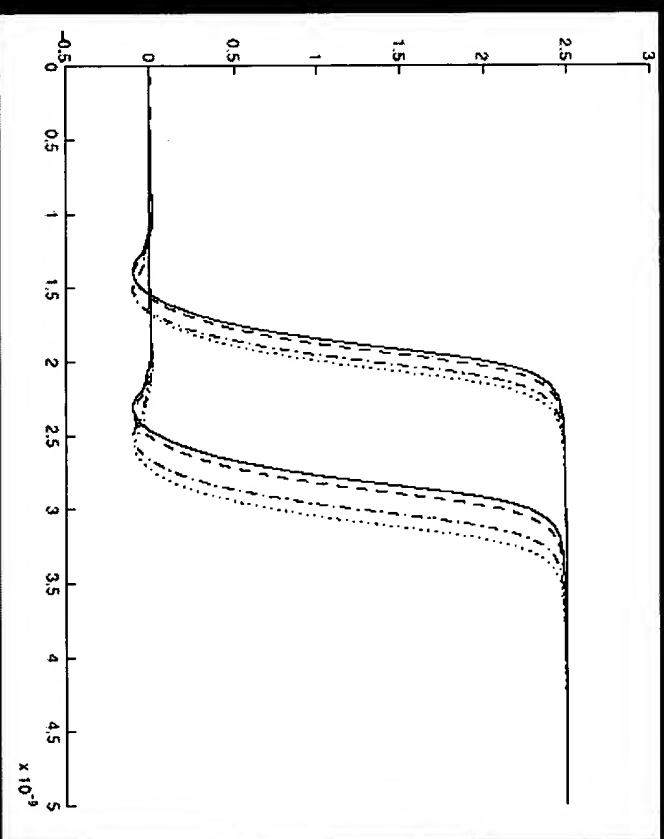
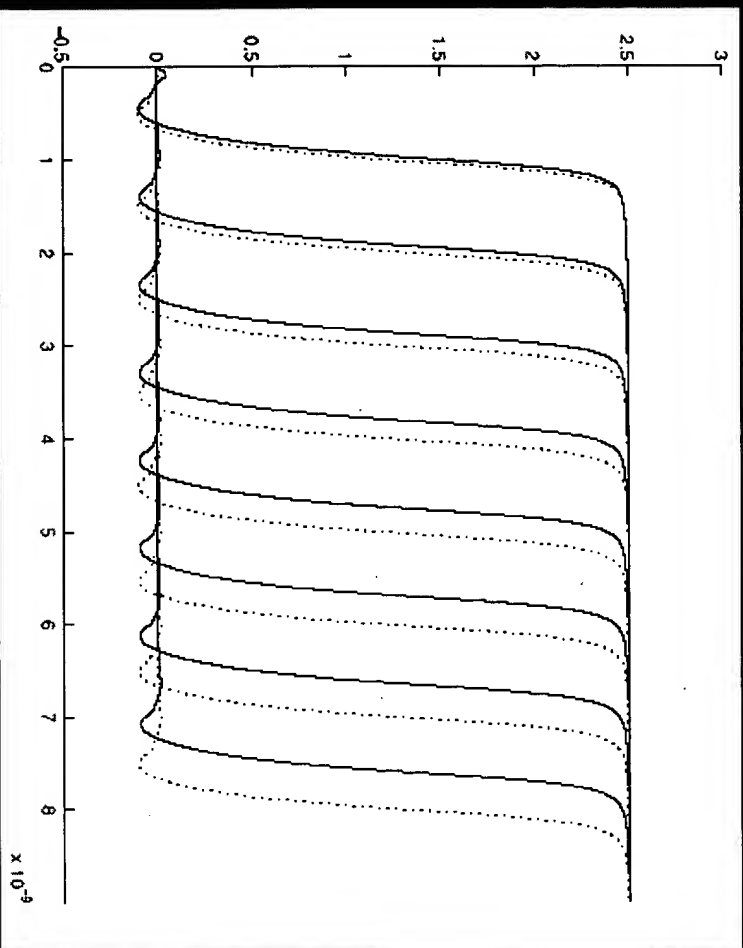
Preliminary timing results

Static ripple-carry adder



16 stages

Preliminary timing results



Stochastic methods for timing and noise?

- Timing tool allows you to immediately identify paths subject to huge “initial condition” delay variability or noise sensitivity that can be reigned in with conservative assumptions of switching activity.
- Body voltages can be applied to static noise analysis
- Integrated timing/noise/body voltage solution required!

Observation: Those circuits that have the most advantage in SOI show the greatest “discrepancy” between initial and steady state results.

